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# *Non-Intrusive Inspection Technologies II*

**Brandon W. Blackburn**
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# Contents

v *Conference Committee*

## SESSION 1 REMOTE SENSING

7310 02 **Optical and engineering development of the spatial heterodyne interferometer for emergent line discrimination spectroscopy (SHIELDS)** [7310-01]
S. Watchorn, J. Noto, Scientific Solutions, Inc. (United States); J. Anderson, U.S. Army Engineer Research and Development Ctr. (United States); C. E. Sioris, Environment Canada (Canada)

7310 03 **The Raytheon-SORDS trimodal imager** [7310-02]
M. V. Hynes, M. Toolin, B. Harris, J. McElroy, Raytheon Co. (United States); M. S. Wallace, L. J. Schultz, M. Galassi, A. Hoover, M. Mocko, D. Palmer, S. Tornga, Los Alamos National Lab. (United States); D. Wakeford, H. R. Andrews, E. T. H. Clifford, L. Li, N. Bray, D. Locklin, Bubble Technology Industries, Inc. (Canada); R. Lanza, B. Horn, Massachusetts Institute of Technology (United States); D. Wehe, Univ. of Michigan (United States)

7310 04 **A solid-state hyperspectral imager for real-time standoff explosives detection using shortwave infrared imaging** [7310-03]
B. M. Onat, G. Carver, M. Itzler, Princeton Lightwave, Inc. (United States)

## SESSION 2 INSPECTION HARDWARE AND MATERIALS

7310 07 **LuAG:Pr, LuAG:La, and LuAP:Ce thin film scintillators for visualisation of x-ray images** [7310-06]
Y. Zorenko, V. Gorbenko, T. Voznyak, Ivan Franko National Univ. of L'viv (Ukraine); T. Martin, P.-A. Douissard, European Synchrotron Radiation Facility (France); J. A. Mares, M. Nikl, Institute of Physics (Czech Republic)

7310 08 **$Lu_3Al_5O_{12}$-based materials for high 2D-resolution scintillation detectors** [7310-07]
M. Nikl, Institute of Physics (Czech Republic); J. Tous, Crytur Ltd. (Czech Republic); J. A. Mares, Institute of Physics (Czech Republic); P. Prusa, Institute of Physics (Czech Republic) and Czech Technical Univ. in Prague (Czech Republic); E. Mihokova, Institute of Physics (Czech Republic) and Univ. of Milano-Bicocca (Italy); K. Blazek, Crytur Ltd. (Czech Republic); A. Vedda, Univ. of Milano-Bicocca (Italy); Yu. Zorenko, V. Gorbenko, Ivan Franko National Univ. of L'viv (Ukraine); V. Babin, Univ. of Tartu (Estonia)

## SESSION 3 INSPECTION METHODOLOGIES AND CONOPS

7310 0B **Real time Muon tomography imaging simulation and fast threat target identification** [7310-10]
H. M. Jaenisch, LSEI Consultants (United States), Johns Hopkins Univ. (United States), James Cook Univ. (Australia), Alabama A&M Univ. (United States), and Amtec Corp. (United States); J. W. Handley, LSEI Consultants (United States) and Amtec Corp. (United States); K. L. Jaenisch, LSEI Consultants (United States); N. G. Albritton, Amtec Corp. (United States)

7310 0C **A quantitative measure for information content in antenna array radiation patterns** [7310-11]
K. D. Mohan, M. A. Khan, A. N. Dharamsi, Old Dominion Univ. (United States)

7310 0D **The SORDS trimodal imager detector arrays** [7310-12]
D. Wakeford, H. R. Andrews, E. T. H. Clifford, L. Li, N. Bray, D. Locklin, Bubble Technology Industries (Canada); M. V. Hynes, M. Toolin, B. Harris, J. McElroy, Raytheon Co. (United States); M. Wallace, Los Alamos National Lab. (United States); R. Lanza, Massachusetts Institute of Technology (United States)

7310 0I **Illicit drug detection using energy dispersive x-ray diffraction** [7310-17]
E. J. Cook, J. A. Griffiths, Univ. College London (United Kingdom); M. Koutalonis, Barts and the London NHS Trust (United Kingdom); C. Gent, Home Office Scientific Development Branch (United Kingdom); S. Pani, J. A. Horrocks, Barts and the London NHS Trust (United Kingdom); L. George, S. Hardwick, Home Office Scientific Development Branch (United Kingdom); R. Speller, Univ. College London (United Kingdom)

*Author Index*

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